

Search Notes



Application/Control No.

10/026,429

Examiner

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Applicant(s)/Patent under Reexamination

OKAJIMA, AIKO

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
399	81-83	9/8/2005	CP
358	1.15,1.12	9/8/2005	CP
358	498	9/8/2005	CP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East (see the search history)	9/8/2005	CP